TOSHIBA Photocoupler IRED & Photo-IC

TLP554

Isolated Line Receiver
Simplex/Multiplex Data Transmission
Computer-Peripheral Interface
Microprocessor System Interfaces
Digital Isolation for A/D, D/A Conversion

The TOSHIBA TLP554 a photocoupler which combines an infrared emitting diode and an integrated high gain, high speed photodetector.

The output of the detector circuit is an open collector, Schottky Clamped transistor.

A Faraday shield integrated on the photodetector chip reduces the effects of capacitive coupling between the input LED emitter and the high gain stages of the detector. This provides an effective common mode transient immunity of 1000 V/µs.

Input Current Threshold

: IF = 5 mA (max)

Switching Speed

: 10 MBd (typ. @NRZ)

Common mode transient immunityGuaranteed Performance over Temperature

: ±1000 V/µs (min) : 0 to 70°C

Isolation Voltage

: 2500 Vrms (min)

UL-recognized

: UL 1577, File No.E67349

cUL-recognized

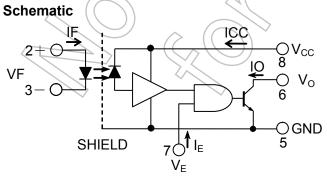
: CSA Component Acceptance Service No.5A

File No.E67349

Unit: mm 9.66±0.25 7.62±0.25 0.25^{±0.10} 0.5±0.1 JEDEC TOSHIBA 11-10C4S Weight: 0.54 g (typ.)

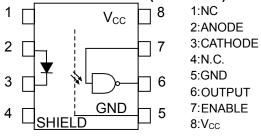
Truth Table

INPUT	ENABLE	OUTPUT
Н	H//	
L	Н	H
Н	L	Н
L		Н



Note: A $0.1\mu F$ bypass capacitor must be connected Between pins 8 and 5.

PIN CONFIGURATION (TOP VIEW)



Start of commercial production 1985-01

TLP554



Recommended Operating Conditions

Characteristic	Symbol	Min	Тур.	Max	Unit
Low Level input Voltage	V _{FL}	-3	0	1.0	V
High Level input current	lFH	6.3 (Note 1)	_	20	mA
Supply Voltage (Note 2)	Vcc	4.5	5	5.5	\
High-Level Enable Voltage	V _{EH}	2.0	_	Vcc	V
Low-Level Enable Voltage	V _{EL}	0	_	0.8	(v)/
Fan Out(TTL Load)	N	_	_	8 (7))
Operating Temperature	Topr	0	<u> </u>	70	<i>?</i>) ℃

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Note 1: 6.3 mA condition permits at least 20 % CTR degradation. Initial switching threshold is 5.0 mA or less.

Note 2: Denotes the operating range, not the recommended operating condition.

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic	Symbol	Rating (Unit	
	Forward current	IF.	20	mA	
	Forward current derating (Ta > 85°C)	ΔΙϝ/ΔΤα	-1.6	mA/°C	
ED	Reverse voltage	V _R //	5	V	
	Input power dissipation	PD	100	mW	
	Input power dissipation derating (Ta > 85°C)	ΔP _D /°C	-2.5	mW/°C	
	Output current	lo 🔷	25	mA	
œ	Output voltage	Vo	-0.5 to 7	V	
DETECTOR	Supply voltage (Note 1)	Aec	7	V	
ETE	Enable voltage (Note 2)	VE	5.5	V	
□	Output power dissipation	Po	40	mW	
	Output power dissipation derating (Ta > 85°C)	ΔΡο/ΔΤα	-2.6	mW/°C	
Stora	ge temperature range	T _{stg} -55 to 125		°C	
Operating temperature range		T _{opr}	-40 to 85	°C	
Lead soldering temperature (10 s) (Note 3)		T _{sol}	260	°C	
Isolation voltage (AC, 60 s, R.H.≤ 60 %) (Note 4)		BVS	2500	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: 60 s Maximum.

Note 2: Not to exceed VCC by more than 500 mV.

Note 3: 2 mm below seating plane.

Note 4: Device considered a two-terminal device :Pins 1, 2, 3 and 4 shorted together,and Pins 5, 6, 7 and 8 shorted together.



Electrical Characteristics

(Unless otherwise specified Ta = 0 to 70°C , Vcc = 4.5 to 5.5 V , VFL \leq 1.0 V)

Characte	eristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Forward Voltage		VF	I _F = 10 mA, Ta=25 °C	_	1.65	1.80	V	
Temperature Coeffic Voltage	cient of Forward	ΔV _F /ΔTa	I _F = 10 mA		-2.0	_	mV/°C	
Input Reverse Curre	nt	IR	V _R = 5 V, Ta = 25 °C	+() }	10	μA	
Input Capacitance		Ст	V _F = 0 V, f = 1MHz, Ta=25 °C		45	_	pF	
Himb I aval Ovtavt C		Land	VF = 1.0 V, VO = 5.5 V VE = 2.0 V		10	250		
High-Level Output Current		Іон	V _F = 1.0 V, V _O = 5.5 V V _E = 2.0 V, Ta = 25°C))~	0.5	10	μΑ	
Low-Level Output Vo	oltage	V _{OL}	IF = 5 mA, VE = 2.0 V IOL = 13 mA (Sinking)	_	0.4	0.6	٧	
High Level input curr	ent	l _{FH}	I _{OL} = 13 mA (Sinking) V _E = 2.0 V, V _{OL} = 0.6 V	<u></u>	5	5	mA	
Supply Current	High Level	Іссн	V _{CC} = 5.5 V, I _F = 0 mA, V _E = 0.5 V		7	15		
Supply Current	Low Level	ICCL	V _{CC} = 5.5 V, I _F = 10 mA V _E = 0.5 V	(4)	12	19	mA	
	High Level	lEH	Vcc = 5.5 V, VE = 2.0 V	7/	-1.0	_	mA	
Enable Current	Low Level	I _{EL}	V _{CC} = 5.5 V, V _E = 0.5 V	<u>)</u>	-1.6	-2.0		
Enable Voltage	High Level	V _{EH}	(Note 1)	2.0	_		V	
Enable Voltage	Low Level	VEL)) – 🏏		_	0.8		
Resistance (Input-Ou	utput)	Rs	V _S = 500 V, R.H. ≤ 60 %, Ta = 25 °C, (Note 2)	5×10 ¹⁰	10 ¹⁴	_	Ω	
Capacitance (Input-C	Output)	Cs	V _S = 0 V, f = 1 MHz, Ta = 25 °C (Note 2)	_	0.6	_	pF	

Note: All typ.values are at Ta = 25 °C

Note 1: No pull up resistor required as the device has an internal pull up resistor.

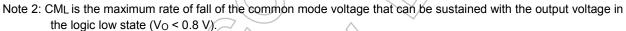
Note 2: Device considered a two-terminal device :Pins 1, 2, 3 and 4 shorted together,and Pins 5, 6, 7 and 8 shorted together.

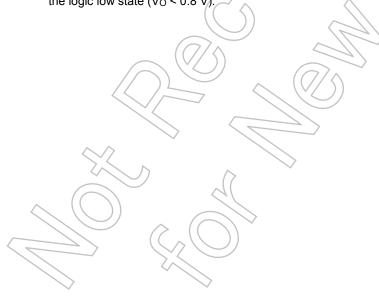
Switching Characteristics (Ta = 25°C, Vcc = 5 V)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation Delay Time (L→H)	t _{pLH}		I_F = 7.5 \rightarrow 0 mA, R_L = 350 Ω C_L = 15 pF	_	60	120	
Propagation Delay Time (H→L)	t _{pHL}		I _F = 0 \rightarrow 7.5 mA, R _L = 350 Ω C _L = 15 pF		60	120	20
Output Rise Time(10-90%)	t _r	'	I _F = 7.5 \rightarrow 0 mA, R _L = 350 Ω C _L = 15 pF	(30	_	ns
Output Fall Time(90-10%)	tf		$I_F = 0 \rightarrow 7.5 \text{ mA}, R_L = 350 \Omega$ C _L = 15 pF	7	30	_	
Enable Propagation Delay Time $(L \rightarrow H)$	tELH	2	$V_E = 0.5 \rightarrow 3.0 \text{ V}, R_L = 350 \Omega$ $I_F = 7.5 \text{ mA}, C_L = 15 \text{ pF}$		25	_	20
Enable Propagation Delay Time $(H \rightarrow L)$	tEHL		$V_E = 3.0 \rightarrow 0.5 \text{ V}, R_L = 350 \Omega$ $I_F = 7.5 \text{ mA}, C_L = 15 \text{ pF}$))'_	25	_	ns
Common Mode Transient Immunity at Hight Level Outout (Note 1)	СМН	3	I _F = 0 mA, R _L = 350 Ω V _{CM} = 400 V, V _{O(min)} = 2 V	1000	10000		\//\u0
Common Mode Transient Immunity at Low Level Outout (Note 2)	CML	3	I _F = 7.5 mA, R _L = 350Ω V _{CM} = 400 V, V _{O(max)} = 0.8 V	-1000	-10000) –	V/µs

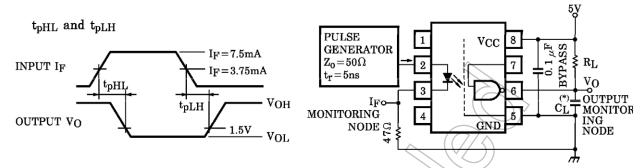
Note: A ceramic capacitor (0.1 μ F) should be connected from pin 8 (V_{CC}) to pin 5 (GND) to stabilize the operation of the high gain linear amplifier. Failure to provide the bypass may impair the switching property. The total lead length between capacitor and coupler should not exceed 1 cm.

Note 1: CMH is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state ($V_0 > 2.0 \text{ V}$)

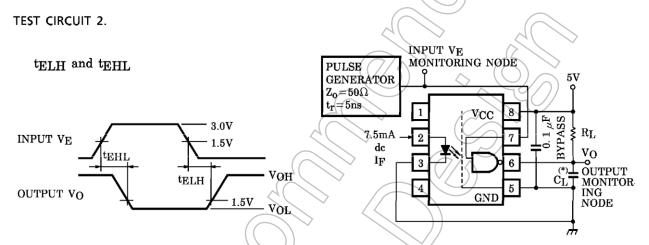




TEST CIRCUIT 1.

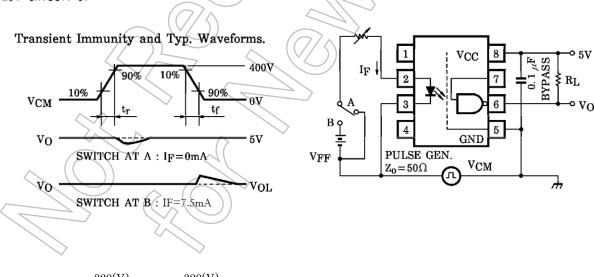


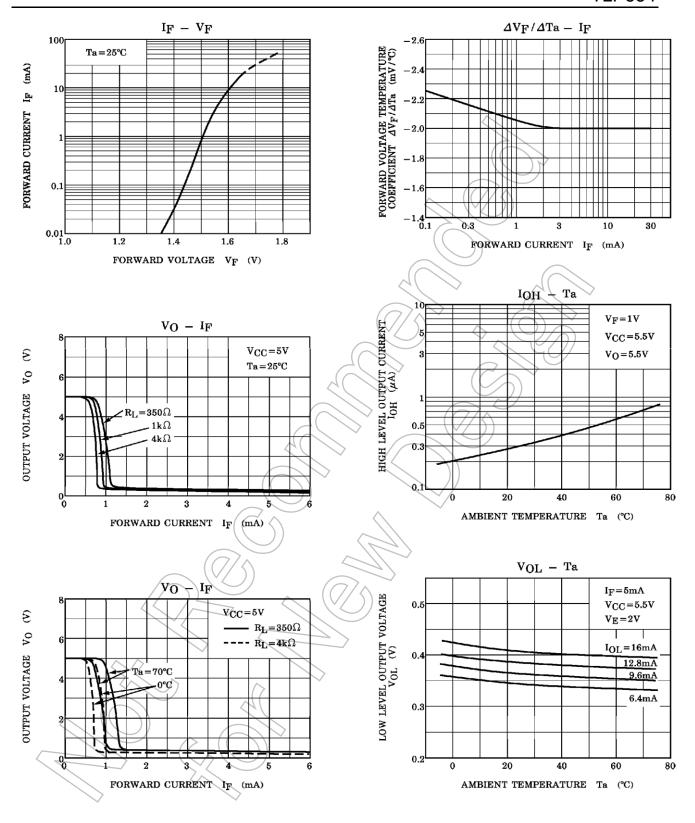
(*) CL is approximately 15pF which includes probe and stray wiring capacitance.



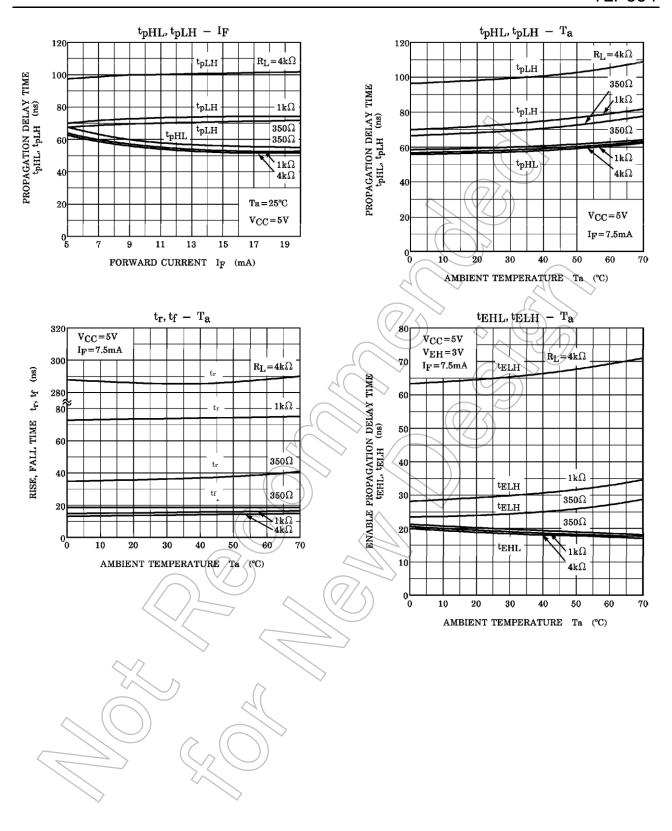
(*) CL is approximately 15pF which includes probe and stray wiring capacitance.







NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



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